

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

ATTY. DOCKET NO.
52433/673

U.S. SERIAL NO.
10/034,061

APPLICANT
MOGI, et al.

FILING DATE
December 27, 2001

GROUP
2832

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE*

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
FTN	H-5-251246	September 28, 1993	Japan				
	H-7-305115	November 21, 1995	Japan			abstract	
	H-8-45751	February 16, 1996	Japan			abstract	
	2000-124044	April 28, 2000	Japan			abstract	
	2000-82622	March 21, 2000	Japan			abstract	
	H-8-111322	April 30, 1996	Japan			abstract	
	H-7-85457	March 31, 1995	Japan			abstract	
	H-8-250339	September 27, 1996	Japan			abstract	
FTN	2001-93583	April 1, 2000	Japan			abstract	

OTHER DOCUMENTS

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
FTN	NOZAWA, et al., "Relationship Between Total Losses Under Tensile Stress in 3 Percent Si-Fe Single Crystals and Their Orientations Near (110)[001]", IEEE Transactions on Magnetics, Vol. MAG14 No. 4, July 1978, pp. 252-257.
FTN	"Development of Orient Core Hi-B", OHM '72/2, February 1972, pp. 1-7.

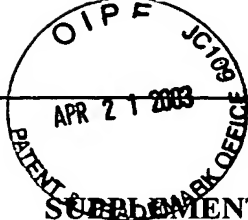
EXAMINER

Touyler Nguyen

DATE CONSIDERED

6/12/03

EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



**SUPPLEMENTAL
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

ATTY. DOCKET NO.
52433/673

U.S. SERIAL NO.
10/034,061

APPLICANT
Hisashi MOGI et al.

FILING DATE
December 27, 2001

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U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE*
TTN	5,188,698	February 23, 1993	Ryuusuke Imai et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
TTN	WO 99/33156	July 1, 1999	United States				
TTN							

OTHER DOCUMENTS

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.	
TTN	Patent Abstracts of Japan, JP 08250339, 27 September 1996.	
TTN	Patent Abstracts of Japan, JP 62001879, 7 January 1987.	

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